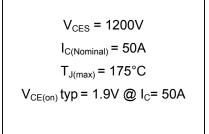


#### INSULATED GATE BIPOLAR TRANSISTOR



# n-channel

## ApplicationsMedium Power Drives

- UPS
- HEV Inverter
- Welding

G	С	E	
Gate	Collector	Emitter	

Features	Benefits
Low V <sub>CE(ON)</sub> and switching Losses	High efficiency in a wide range of applications
10μs Short Circuit SOA and Square RBSOA	Rugged Transient Performance
Maximum Junction Temperature 175°C	Increased Reliability
Positive V <sub>CE (ON)</sub> Temperature Coefficient	Excellent current sharing in parallel operation

Page next number	Dookogo Typo	Standa	rd Pack	Orderable part number	
Base part number	Package Type	Form	Quantity		
IRG7CH54K10EF-R	Die on film	Wafer	1	IRG7CH54K10EF-R	

#### **Mechanical Parameter**

Die Size	7.55 x 7.55	mm <sup>2</sup>		
Minimum Street Width	75	μm		
Emiter Pad Size (Included Gate Pad)	See Die Drawing			
Gate Pad Size	1.0 x 0.7	mm <sup>2</sup>		
Area Total / Active	57/39.64			
Thickness	140	μm		
Wafer Size	200	mm		
Flat Position	0	Degrees		
Maximum-Possible Chips per Wafer	465 pcs			
Passivation Front side	Silicon Nitride			
Front Metal	Al, Si (4μm)			
Backside Metal	Al- Ti - Ni- Ag (1kA°-1kA°-4kA°-6kA°)			
Die Bond	Electrically conductive epoxy or solder			
Reject Ink Dot Size	0.25 mm diameter minimum			



**Maximum Ratings** 

	Parameter	Max.	Units
$V_{CE}$	Collector-Emitter Voltage, T <sub>J</sub> =25°C	1200	V
I <sub>C</sub>	DC Collector Current	①	Α
I <sub>LM</sub>	Clamped Inductive Load Current ②	200	Α
$V_{\sf GE}$	Gate Emitter Voltage	± 30	V
$T_J$ , $T_{STG}$	Operating Junction and Storage Temperature	-40 to +175	°C

Static Characteristics (Tested on wafers) . T<sub>J</sub>=25°C

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)CES</sub>	Collector-to-Emitter Breakdown Voltage	1200				V <sub>GE</sub> = 0V, I <sub>C</sub> = 250μA ③
$V_{CE(sat)}$	Collector-to-Emitter Saturated Voltage		1.45	1.70	V	$V_{GE} = 15V, I_{C} = 15A, T_{J} = 25^{\circ}C$
$V_{GE(th)}$	Gate-Emitter Threshold Voltage	5.0		7.5		$I_C = 2.4 \text{mA}$ , $V_{GE} = V_{CE}$
I <sub>CES</sub>	Zero Gate Voltage Collector Current		1.0	25	μΑ	$V_{CE} = 1200V, V_{GE} = 0V$
$I_{GES}$	Gate Emitter Leakage Current			± 200	nA	$V_{CE} = 0V, V_{GE} = \pm 30V$

Electrical Characteristics (Not subject to production test- Verified by design/characterization)

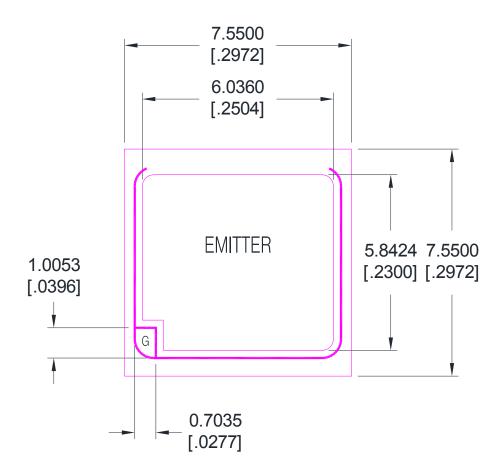
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	Parameter	Min.	Тур.	Max.	Units	Conditions
\/	Collector to Emitter Saturated Voltage		1.9	2.3	V	V <sub>GE</sub> = 15V, I <sub>C</sub> = 50A , T <sub>J</sub> = 25°C ④
$V_{CE(sat)}$	Collector-to-Emitter Saturated Voltage		2.5		V	$V_{GE} = 15V, I_{C} = 50A, T_{J} = 175^{\circ}C$
SCSOA	Short Circuit Safe Operating Area	10			l us	$V_{GE}$ =15V, $V_{CC}$ =600V, ⑤ Rg = 5 $\Omega$ , , Vp ≤1200V , $T_{J}$ = 150°C
RBSOA	Reverse Bias Safe Operating Area	FULL SQUARE			I	$T_J$ = 175°C, $I_C$ = 200A $V_{CC}$ = 960V, $V_D \le 1200V$ $Rg = 5\Omega$ , $V_{GE}$ = +20V to 0V
C <sub>iss</sub>	Input Capacitance		5740			V <sub>GE</sub> = 0V
Coss	Output Capacitance		220		pF	V <sub>CE</sub> = 30V
$C_{rss}$	Reverse Transfer Capacitance		130			f = 1.0MHz,
$Q_g$	Total Gate Charge (turn-on)	_	240			I <sub>C</sub> = 50A ⑥
$Q_{ge}$	Gate-to-Emitter Charge (turn-on)	_	60		nC	V <sub>GE</sub> = 15V
$Q_{gc}$	Gate-to-Collector Charge (turn-on)		110			V <sub>CC</sub> = 600V

Switching Characteristics (Inductive Load-Not subject to production test-Verified by design/characterization)

	Parameter	Min.	Тур.	Max.	Units	Conditions ⊚⑦
t <sub>d(on)</sub>	Turn-On delay time	_	75	_		$I_{\rm C} = 50$ A, $V_{\rm CC} = 600$ V
t <sub>r</sub>	Rise time	_	60	_		$R_G = 5\Omega$ , $V_{GE} = 15V$ , $L = 200\mu H$
$t_{d(off)}$	Turn-Off delay time	_	305	_		T <sub>J</sub> = 25°C
t <sub>f</sub>	Fall time	_	55	_	Ī	
t <sub>d(on)</sub>	Turn-On delay time	_	70	_	ns	$I_{\rm C} = 50$ A, $V_{\rm CC} = 600$ V
t <sub>r</sub>	Rise time	_	60	_		$R_G = 5\Omega$ , $V_{GE} = 15V$ , $L = 200 \mu H$
$t_{d(off)}$	Turn-Off delay time	_	345	_		T <sub>J</sub> = 175°C
$t_f$	Fall time	_	185	_		



### Die Drawing



#### NOTES:

- 1. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 2. CONTROLLING DIMENSION: INCHES
- 3. DIE WIDTH AND LENGTH TOLERANCE: -0.0508 [.002]
- 4. DIE THICKNESS = 0.140 [.0055]

#### Notes:

- $\odot$  The current in the application is limited by  $T_{JMax}$  and the thermal properties of the assembly.
- ②  $V_{CC}$  = 80% ( $V_{CES}$ ),  $V_{GE}$  = 20V, L = 19μH,  $R_G$  = 5Ω. ③ Refer to AN-1086 for guidelines for measuring  $V_{(BR)CES}$  safely
- Die Level Characterization
- ⑤ Not subject to production test-Verified by design / characterization
- © Pulse width limited by junction temperature
- Values influenced by parasitic L and C in measurement



#### **Additional Testing and Screening**

For Customers requiring product supplied as Known Good Die (KGD) or requiring specific die level testing, please contact your local IR Sales.

#### **Shipping**

Sawn Wafer on Film. Please contact your local IR sales office for non-standard shipping options

#### Handling

- Product must be handled only at ESD safe workstations. Standard ESD precautions and safe work environments are as defined in MIL-HDBK-263.
- Product must be handled only in a class 10,000 or better-designated clean room environment.
- Singulated die are not to be handled with tweezers. A vacuum wand with a non-metallic ESD protected tip should be used.

#### Wafer/Die Storage

- Proper storage conditions are necessary to prevent product contamination and/or degradation after shipment.
- Note: To reduce the risk of contamination or degradation, it is recommended that product not being used in the
  assembly process be returned to their original containers and resealed with a vacuum seal process.
- Sawn wafers on a film frame are intended for immediate use and have a limited shelf life.

#### **Further Information**

For further information please contact your local IR Sales office or email your enquiry to <a href="http://die.irf.com">http://die.irf.com</a>

Data and specifications subject to change without notice. This product has been designed and qualified for Industrial market.

Qualification Standards can be found on IR's Web site.



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Visit us at www.irf.com for sales contact information.